

Search Notes

Application No.

10/604,244

Examiner

Toan M Le

Applicant(s)

TAI ET AL.

Art Unit

2863

SEARCHED

Class	Subclass	Date	Examiner
702	84	8/31/2004	TL
700	109	8/31/2004	TL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Wafer In-line Yield Prediction	9/1/2004	TL
Wafer Yield Analysis; Statistical; Regression; Sample	9/1/2004	TL
Wafer Quality Control Analysis; Parameter; Lot; Sample	8/31/2004	TL
Quality Control, Sample, Parameter, Search, Database, Analyzing, Correlating, Wafer	8/31/2004	TL